

Notice of References Cited

Application/Control No.

10/579,238

Applicant(s)/Patent Under
Reexamination
TANAKA ET AL.

Examiner

SANG Y. PAIK

Art Unit

3742

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,753,548	06-2004	Ogawa et al.	257/53
*	B	US-2003/0063630	04-2003	Sakai et al.	372/10
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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